

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10629319	07/29/2003	360	324.110	2653	HEINZ, A

**\*\*APPLICANTS:** Hardayal Gill; Wen-Chien Hsiao; Jih-Shiuan Luo;

**\*\*CONTINUING DATA VERIFIED:**

**\*\* FOREIGN APPLICATIONS VERIFIED:**

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials <i>SH</i>		ATTORNEY DOCKET NO HSJ920030016US1 (HITG.023)	
<b>TITLE :</b> Method and apparatus for enhancing thermal stability, improving biasing and reducing damage from electrostatic discharge in self-pinned abutted junction. Leads having self-pinned layer			
<small>U.S. DEPT. OF COMM./PAT. &amp; TM.-PTO-436L (Rev. 12-94)</small>			